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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Sheet 1 of 2

Complete If Known	
Application Number	10/630,537
Filing Date	July 29, 2003
First Named Inventor	Sandeep BHATIA
Art Unit	2138
Examiner Name	Phung M. CHUNG
Attorney Docket Number	CA7034222001

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No.[1]	Document Number: Number - Kind Code[2] (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
PC	1	US- 6,079,040 A	06/20/2002	Hom et al.	
PC	2	US- 6,418,545 B1	07/09/2002	Adusumilli	
PC	3	US- 6,901,544 B1	05/31/2005	Huth et al.	
PC	4	US- 2003/0204802 A1	10/30/2003	Sim	
PC	5	US- 2004/0078741 A1	04/22/2004	Morton	

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No.[1]	Foreign Patent Document: Country Code[3] - Number[4] - Kind Code[5] (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T[6]
PC	6	JP-2003-202362	07/18/2003	NEC Microsystems Ltd.		

Examiner Signature	/Phung Chung/	Date Considered	01/17/2007

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Sheet 2 of 2

Complete if Known	
Application Number	10/630,537
Filing Date	July 29, 2003
First Named Inventor	Sandeep BHATIA
Art Unit	2138
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Attorney Docket Number	CA7034222001

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials *	Cite No.[1]	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T[2]
PC	1	BALAKRISHNAN, K. J., et al., *"Deterministic Test Vector Decompression in Software Using Linear Operations"*, Proceedings of the 21st IEEE VLSI Test Symposium, April 27 - May 1, 2003, pp. 225 - 231, IEEE, Los Alamitos, CA, USA.	
PC	2	BARDELL, P. H. et al., *"Build-In Test for VLSI: Pseudorandom Techniques"*, 1987, pp. 61-313, John Wiley and Sons, New York, USA.	
PC	3	BHATIA, S., *"Test Compaction by Using Linear-Matrix Driven Scan Chains"*, Proceedings of the 18th IEEE International Symposium on Defect and Fault Tolerance in VLSI Systems, November 3 - 5, 2003, pp. 185 - 190, IEEE, USA.	
PC	4	BHATIA, S., *"Test Compaction in a Parallel Access Scan Environment"*, Proceedings of the 6th Asian Test Symposium (ATS '97), November 17 - 19, 1997, pp. 300 -305, IEEE, Los Alamitos, CA, USA.	
PC	5	HELLEBRAND. S., et al., *"Generation of Vector Patterns Through Reseeding of Multiple-Polynomial Linear Feedback Shift Registers"*, Proceedings of the International Test Conference, 1992, pp. 120 -124, France.	
PC	6	HSU, F. F. et al., *"A Case Study on the Implementation of the Illinois Scan Architecture"*, Proceedings of the International Test Conference; 2001, pp. 538 - 547, International Test Conference, Washington, D.C., USA.	
PC	7	JARAMILLO, K. et al., *"10 Tips for Successful Scan Design: Part One"*; February 17, 2000, endmag.com, pp. 67 - 73, 75; USA.	
PC	8	JARAMILLO, K. et al., *"10 Tips for Successful Scan Design: Part Two"*; February 17, 2000, endmag.com, pp. 77, 78, 80, 82, 84, 86, 88, 90; USA.	
PC	9	KIEFER, G. et al., *"Deterministic BIST with Multiple Scan Chains"*, Proceedings of the International Test Conference, 1998, pp. 1057 - 1064, International Test Conference, Washington, D.C., USA.	
PC	10	KRISHNA, C.V. et al., *"Reducing Test Data Volume Using LFSR Reseeding with Seed Compression"*, Proceedings of the International Test Conference, 2002, pp. 321 - 330, International Test Conference, Washington, D.C., USA.	
PC	11	McCLUSKEY, E. J., *"Test Data Compression"*, Design & Test of Computers, March - April 2003, pp. 76 - 87, Volume 20, Issue 2, IEEE Computer Society and the IEEE Circuits and Systems Society, USA.	
PC	12	RAJSKI, J. et al., *"Embedded Deterministic Test for Low Cost Manufacturing Test"*, Proceedings of the International Test Conference, 2002, pp. 310 - 310, International Test Conference, Washington, D. C., USA.	

Examiner Signature	/Phung Chung/	Date Considered	01/17/2007

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